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Renesas Technology Corp. Customer Support Dept. April 1, 2003



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Silicon N Channel MOS FET Series Power Switching



ADE-208-353D (Z) 5th. Edition Mar. 1997

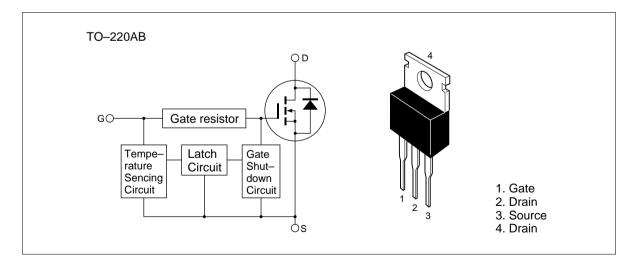
Features

This FET has the over temperature shut-down capability sensing to the junction temperature.

This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

- Logic level operation (4 to 6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut-down operation (Need 0 voltage recovery)

Outline



Absolute Maximum Ratings ($Ta = 25^{\circ}C$)

Item	Symbol	Ratings	Unit	
Drain to source voltage	V _{DSS}	60	V	
Gate to source voltage	V _{GSS}	16	V	
Gate to source voltage	V _{GSS}	-2.8	V	
Drain current	I _D	20	А	
Drain peak current	Note1 D(pulse)	40	А	
Body-drain diode reverse drain current	I _{DR}	20	А	
Channel dissipation	Pch Note2	50	W	
Channel temperature	Tch	150	°C	
Storage temperature	Tstg	-55 to +150	°C	

Note: 1. $PW \le 10\mu s$, duty cycle $\le 1 \%$

2. Value at Ta = $25^{\circ}C$

Typical Operation Characteristics

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Input voltage	V _{IH}	3.5	_	—	V	
	VIL	—	—	1.2	V	
Input current	I _{IH1}	_	—	100	μA	Vi = 8V, V _{DS} = 0
(Gate non shut down)	I _{IH2}	—	—	50	μA	$Vi = 3.5V, V_{DS} = 0$
	IL	—	—	1	μA	$Vi = 1.2V, V_{DS} = 0$
Input current	I IH(sd)1	—	0.8	—	mA	$Vi = 8V, V_{DS} = 0$
(Gate shut down)	I _{IH(sd)2}	—	0.35	—	mA	$Vi = 3.5V, V_{DS} = 0$
Shut down temperature	T_{sd}	_	175	—	°C	Channel temperature
Gate operation voltage	V _{op}	3.5	_	13	V	

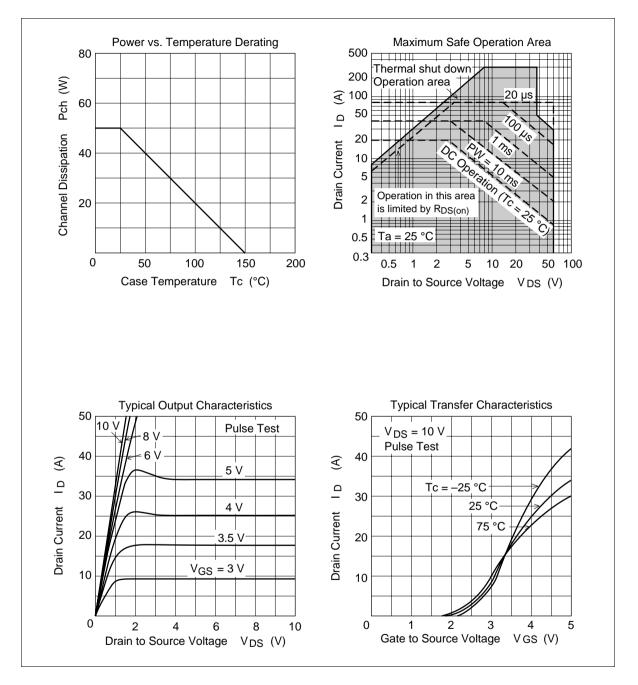
Electrical Characteristics (Ta = 25°C)

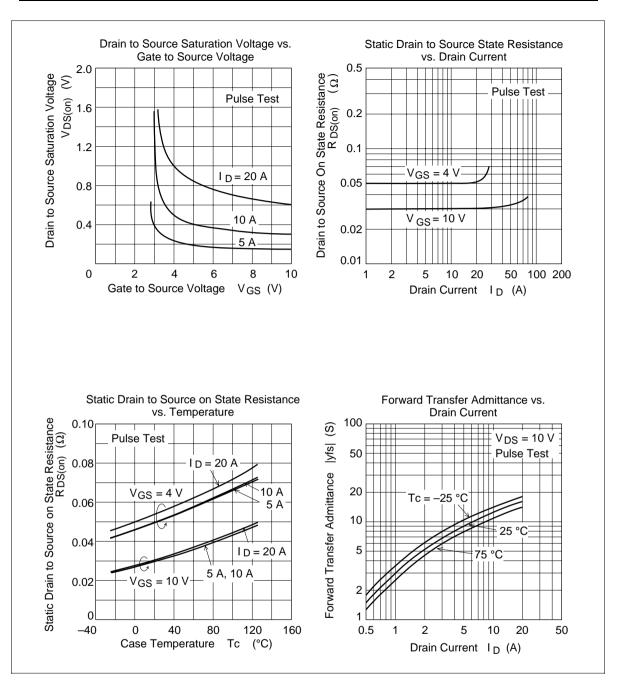
Item	Symbol	Min	Тур	Мах	Unit	Test Conditions
Drain current	I _{D1}	10	_	_	А	$V_{GS} = 3.5V, V_{DS} = 2V$
Drain current	I _{D2}		_	10	mA	$V_{GS} = 1.2V, V_{DS} = 2V$
Drain to source breakdown voltage	$V_{(BR)DSS}$	60	—	—	V	$I_{\rm D} = 10 {\rm mA}, V_{\rm GS} = 0$
Gate to source breakdown voltage	$V_{(\text{BR})\text{GSS}}$	16	—	—	V	$I_{G} = 100 \mu A, V_{DS} = 0$
Gate to source breakdown voltage	$V_{(\text{BR})\text{GSS}}$	-2.8	—	—	V	$I_{g} = -100 \mu A, V_{DS} = 0$
Gate to source leak current	I _{GSS1}	_	_	100	μA	$V_{GS} = 8V, V_{DS} = 0$
	I _{GSS2}	_	_	50	μA	$V_{GS} = 3.5V, V_{DS} = 0$
	I _{GSS3}	_	_	1	μA	$V_{GS} = 1.2V, V_{DS} = 0$
	I _{GSS4}	_	_	-100	μA	$V_{GS} = -2.4V, V_{DS} = 0$
Input current (shut down)	GS(op)1	_	0.8		mA	$V_{GS} = 8V, V_{DS} = 0$
	I _{GS(op)2}	_	0.35		mA	$V_{GS} = 3.5V, V_{DS} = 0$
Zero gate voltege drain current	I _{DSS}	—	—	250	μΑ	$V_{\rm DS} = 50 \ V, \ V_{\rm GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	1.0	_	2.25	V	$I_{\rm D} = 1$ mA, $V_{\rm DS} = 10$ V
Static drain to source on state resistance	$R_{DS(on)}$	—	50	65	mΩ	$I_{\rm D} = 10 \text{A}, \ V_{\rm GS} = 4 \text{V}^{\text{Note3}}$
Static drain to source on state resistance	$R_{\text{DS(on)}}$	—	30	43	mΩ	$I_{D} = 10A, V_{GS} = 10V^{Note3}$
Forward transfer admittance	y _{fs}	6	12	_	S	$I_{\rm D} = 10$ A, $V_{\rm DS} = 10 V^{\rm Note3}$
Output capacitance	Coss	_	630	_	pF	$V_{DS} = 10V$, $V_{GS} = 0$ f = 1 MHz
Turn-on delay time	t _{d(on)}		7.5		μs	$I_{\rm D} = 5A, V_{\rm GS} = 5V$
Rise time	t,	_	29		μs	$R_{L} = 6\Omega$
Turn-off delay time	t _{d(off)}	_	34		μs	
Fall time	t _f	_	26		μs	
Body-drain diode forward	V_{DF}	_	1.0	_	V	$I_{\rm F} = 20$ A, $V_{\rm GS} = 0$
voltage						
Body-drain diode reverse	t _{rr}	_	110		ns	$I_{F} = 20A, V_{GS} = 0$
recovery time						diF/ dt =50A/µs
Over load shut down	t _{os1}		1.8	_	ms	$V_{GS} = 5V, V_{DD} = 12V$
operation time Note4	t _{os2}	—	0.7		ms	$V_{GS} = 5V, V_{DD} = 24V$

Note: 3. Pulse test

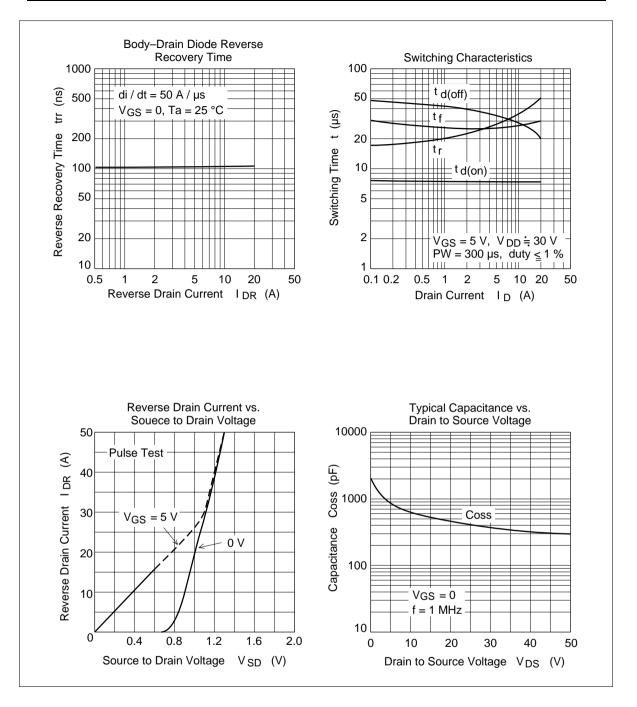
4. Include the time shift based on increasing of channel temperature when operate under over load condition.

Main Characteristics

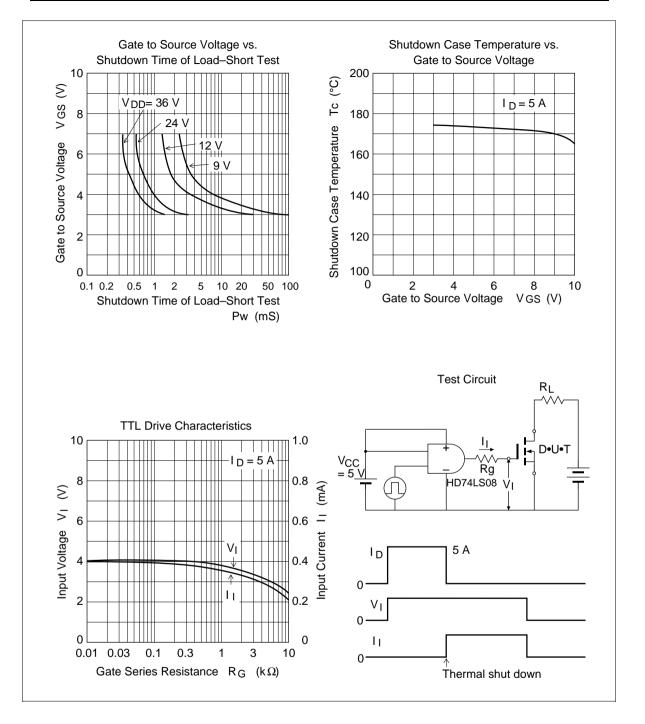


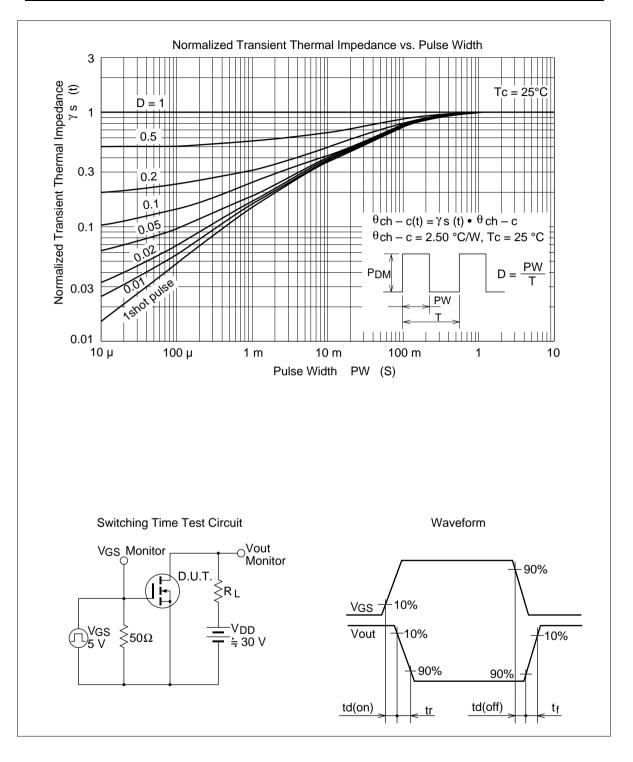


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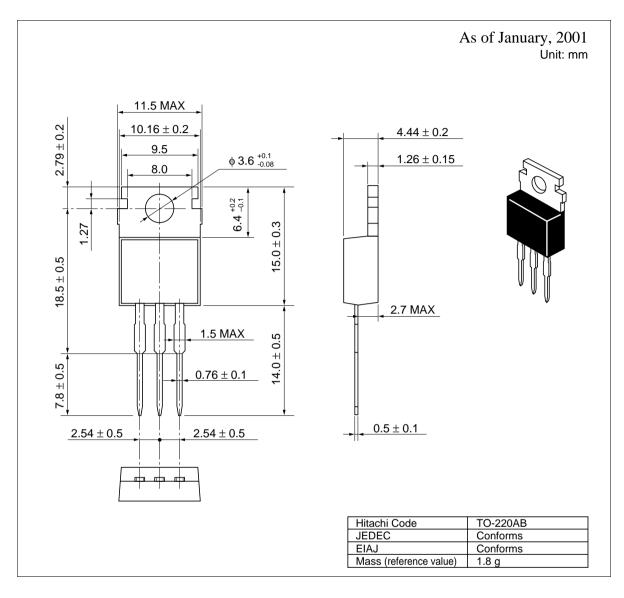


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Package Dimensions



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